Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
10/697,028	KIM, JIN K.
Examiner	Art Unit
Leith A. Al-Nazer	2821

SEARCHED			
Class	Subclass	Date	Examiner
372	43.01- 46.016	11/21/2005	LA
	. :		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	-			
	1			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST prior art text search (see "Examiner Search Notes")	11/21/2005	LA